

PowerMOS transistor

GENERAL DESCRIPTION

N-channel enhancement mode field-effect power transistor in a plastic envelope.

The device is intended for use in Switched Mode Power Supplies (SMPS), motor control, welding, DC/DC and AC/DC converters, and in general purpose switching applications.

QUICK REFERENCE DATA

SYMBOL	PARAMETER	BUK454	MAX.	MAX.	UNIT
V_{DS}	Drain-source voltage	-400A	-400B		V
I_D	Drain current (DC)	400	400		A
P_{tot}	Total power dissipation	4.6	4.2		W
$R_{DS(ON)}$	Drain-source on-state resistance	75	75		Ω
		1.5	1.8		

MECHANICAL DATA

Dimensions in mm

Net Mass: 2g

Pinning:

1 = Gate

2 = Drain

3 = Source

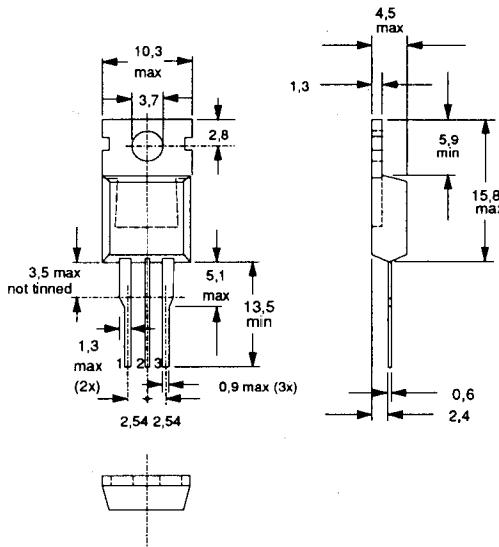
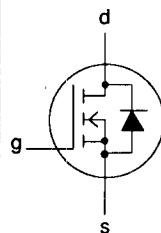


Fig.1 TO220AB; drain connected to mounting base.

blue binder, tab 4

Notes

- Observe the general handling precautions for electrostatic-discharge sensitive devices (ESDs) to prevent damage to MOS gate oxide.
- Accessories supplied on request: refer to Mounting instructions for TO220 envelopes.

RATINGS

Limiting values in accordance with the Absolute Maximum System (IEC 134)

SYMBOL	PARAMETER	CONDITIONS	MIN.	MAX.	UNIT
V_{DS} V_{DGR} $\pm V_{GS}$	Drain-source voltage	$R_{GS} = 20 \text{ k}\Omega$	-	400	V
	Drain-gate voltage		-	400	V
	Gate-source voltage		-	30	V
I_D I_D I_{DM}	Drain current (DC)	$T_{mb} = 25^\circ\text{C}$ $T_{mb} = 100^\circ\text{C}$ $T_{mb} = 25^\circ\text{C}$	-	-400A	A
	Drain current (DC)		-	4.6	A
	Drain current (pulse peak value)		-	2.9	A
P_{tot} $T_{Storage}$ T_J	Total power dissipation	$T_{mb} = 25^\circ\text{C}$	-	18	A
	Storage temperature		-55	75	W
	Junction Temperature		-	150	°C
			-	150	°C

THERMAL RESISTANCES

From junction to mounting base	$R_{th,j(mb)} = 1.67 \text{ K/W}$
From junction to ambient	$R_{th(j,a)} = 60 \text{ K/W}$

STATIC CHARACTERISTICS $T_{mb} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT	
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}; I_D = 0.25 \text{ mA}$	400	-	-	V	
$V_{GS(TO)}$	Gate threshold voltage	$V_{DS} = V_{GS}; I_D = 1 \text{ mA}$	2.1	3.0	4.0	V	
I_{oss}	Zero gate voltage drain current	$V_{DS} = 400 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25^\circ\text{C}$	-	2	20	μA	
I_{oss}	Zero gate voltage drain current	$V_{DS} = 400 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 125^\circ\text{C}$	-	0.1	1.0	mA	
I_{gss}	Gate source leakage current	$V_{GS} = \pm 30 \text{ V}; V_{DS} = 0 \text{ V}$	-	10	100	nA	
$R_{DS(ON)}$	Drain-source on-state resistance	$V_{GS} = 10 \text{ V}; I_D = 1.5 \text{ A}$	BUK454-400A		1.3	1.5	Ω
			BUK454-400B		1.5	1.8	Ω

DYNAMIC CHARACTERISTICS $T_{mb} = 25^\circ\text{C}$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
g_{fs}	Forward transconductance	$V_{DS} = 25 \text{ V}; I_D = 1.5 \text{ A}$	2.1	2.5	-	S
C_{iss} C_{oss} C_{res}	Input capacitance Output capacitance Feedback capacitance	$V_{GS} = 0 \text{ V}; V_{DS} = 25 \text{ V}; f = 1 \text{ MHz}$	-	360	500	pF
$-$ t_d t_r t_d t_f	Turn-on delay time Turn-on rise time Turn-off delay time Turn-off fall time	$V_{DD} = 30 \text{ V}; I_D = 2.5 \text{ A};$ $V_{GS} = 10 \text{ V}; R_{GS} = 50 \Omega;$ $R_{gen} = 50 \Omega$	-	15 40 50 30	20 60 65 40	ns ns ns ns
L_d L_d L_s	Internal drain inductance Internal drain inductance Internal source inductance	Measured from contact screw on tab to centre of die Measured from drain lead 6 mm from package to centre of die Measured from source lead 6 mm from package to source bond pad	-	3.5 4.5 7.5	-	nH

REVERSE DIODE RATINGS AND CHARACTERISTICS

 $T_{mb} = 25^\circ C$ unless otherwise specified

SYMBOL	PARAMETER	CONDITIONS	MIN.	TYP.	MAX.	UNIT
I_{DR}	Continuous reverse drain current	-	-	-	4.6	A
I_{DRM}	Pulsed reverse drain current	-	-	-	18	A
V_{SD}	Diode forward voltage	$I_F = 4.6 \text{ A}; V_{GS} = 0 \text{ V}$	-	1.1	1.4	V
t_{rr}	Reverse recovery time	$I_F = 4.6 \text{ A}; -dI_F/dt = 100 \text{ A}/\mu\text{s}; V_{GS} = 0 \text{ V}; V_R = 100 \text{ V}$	-	300	-	ns
Q_{rr}	Reverse recovery charge		-	2.5	-	μC

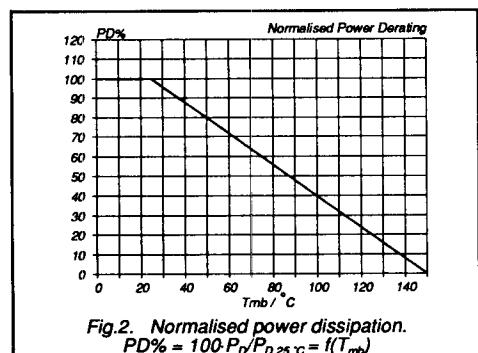


Fig.2. Normalised power dissipation.
 $PD\% = 100 \cdot P_D / P_{D,25^\circ C} = f(T_{mb})$

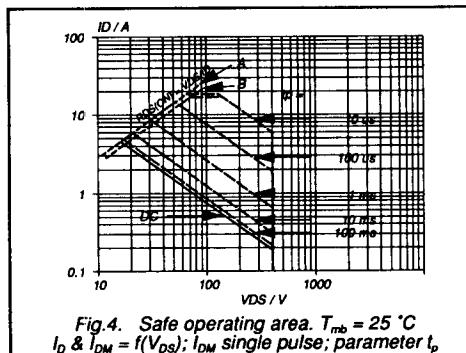


Fig.4. Safe operating area. $T_{mb} = 25^\circ C$
 I_D & $I_{DM} = f(V_{DS}); I_{DM}$ single pulse; parameter t_p

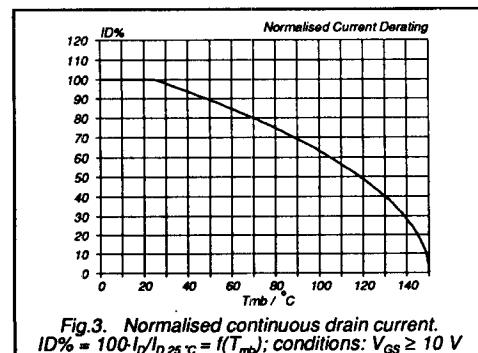


Fig.3. Normalised continuous drain current.
 $ID\% = 100 \cdot I_D / I_{D,25^\circ C} = f(T_{mb})$; conditions: $V_{GS} \geq 10 \text{ V}$

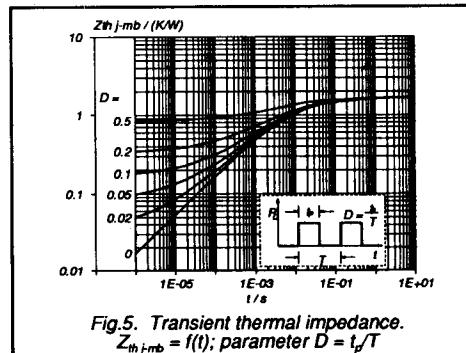


Fig.5. Transient thermal impedance.
 $Z_{th,j-mb} = f(t)$; parameter $D = t_p/T$

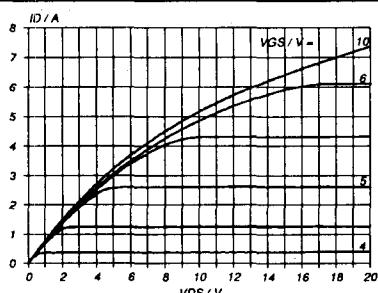


Fig.6.¹ Typical output characteristics, $T_j = 25^\circ\text{C}$.
 $I_D = f(V_{DS})$; parameter V_{GS}

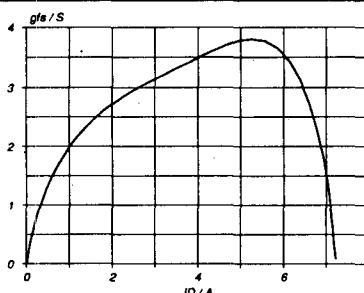


Fig.9. Typical transconductance, $T_j = 25^\circ\text{C}$.
 $g_{fs} = f(I_D)$; conditions: $V_{DS} = 25\text{V}$

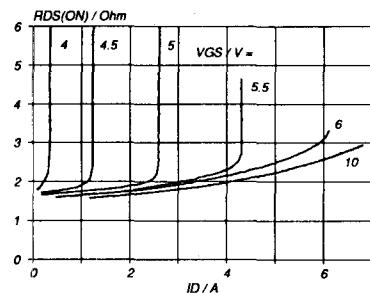


Fig.7. Typical on-state resistance, $T_j = 25^\circ\text{C}$.
 $R_{DS(ON)} = f(I_D)$; parameter V_{GS}

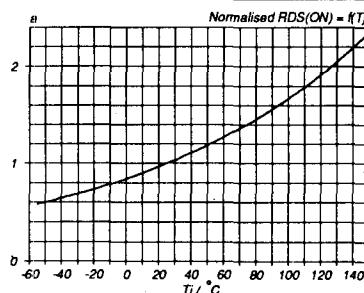


Fig.10. Normalised drain-source on-state resistance.
 $a = R_{DS(ON)}/R_{DS(ON)25^\circ\text{C}} = f(T_j)$; $I_D = 1.5\text{A}$; $V_{GS} = 10\text{V}$

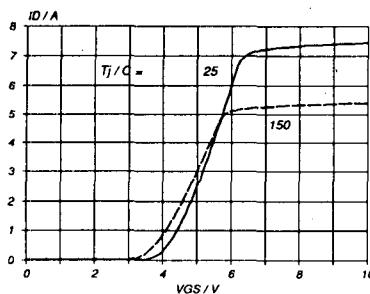


Fig.8. Typical transfer characteristics.
 $I_D = f(V_{GS})$; conditions: $V_{DS} = 25\text{V}$; parameter T_j

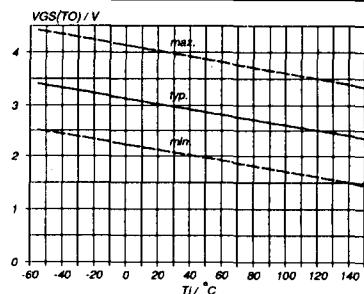


Fig.11. Gate threshold voltage.
 $V_{GS(TO)} = f(T_j)$; conditions: $I_D = 1\text{mA}$; $V_{DS} = V_{GS}$

